

SWF5N80-VB Datasheet

N-Channel 800V (D-S) Super Junction Power MOSFET

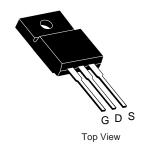
PRODUCT SUMMARY				
V _{DS} (V)	800			
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V 1.2			
Q _g (Max.) (nC)	200			
Q _{gs} (nC)	24			
Q _{gd} (nC)	110)		
Configuration	Single			

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	800	V	
Gate-Source Voltage		V _{GS}	± 30	7 °	
Continuous Drain Current	V_{GS} at 10 V $T_C = 25 ^{\circ}\text{C}$	I-	5	А	
	$T_C = 100 ^{\circ}C$	I _D	3.9		
Pulsed Drain Current ^a		I _{DM}	21	1	
Linear Derating Factor			1.5	W/°C	
Single Pulse Avalanche Energy ^b		E _{AS}	770	mJ	
Repetitive Avalanche Current ^a		I _{AR}	7.8	Α	
Repetitive Avalanche Energy ^a		E _{AR}	19	mJ	
Maximum Power Dissipation	T _C = 25 °C	P _D	190	W	
Peak Diode Recovery dV/dt ^c		dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
Mounting Torque	0-32 OF IVIS SCIEW		1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 23 mH, R_g = 25 Ω , I_{AS} = 7.8 A (see fig. 12). c. I_{SD} \leq 7.8 A, dl/dt \leq 140 A/ μ s, V_{DD} \leq 600 V, T_J \leq 150 °C.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	40	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.65	

PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D = 250 μA	800	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} :	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} :	= 800 V, V _{GS} = 0 V	-	-	100	μA
2010 date Voltage Brain Garrent	יטפטי	$V_{DS} = 640 \text{V}$	V, V _{GS} = 0 V, T _J = 125 °C	-	-	500	μ, τ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	$I_D = 3.7 A^b$	-	1.2	-	Ω
Forward Transconductance	9fs	V _{DS} =	= 100 V, I _D = 3.7 A ^b	5.6	-	-	S
Dynamic							
Input Capacitance	C_{iss}		V _{GS} = 0 V,		3100	-	
Output Capacitance	C _{oss}	1	$V_{DS} = 25 \text{ V},$	-	800	-	рF
Reverse Transfer Capacitance	C_{rss}	f = 1	.0 MHz, see fig. 5	-	490	-	
Total Gate Charge	Qg			-	-	200	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 3.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b	-	-	24	nC
Gate-Drain Charge	$Q_{\sf gd}$		ground to	-	-	110	
Turn-On Delay Time	t _{d(on)}			-	19	-	
Rise Time	t _r	V _{DD} =	$= 400 \text{ V}, I_D = 3.8 \text{ A},$	-	38	-	no
Turn-Off Delay Time	t _{d(off)}	R_g = 6.2 Ω, R_D = 52 Ω see fig. 10 ^b		-	120	-	ns
Fall Time	t _f			ı	39	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	-11
Internal Source Inductance	L _S			-	13	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	Is	MOSFET sym	MOSFET symbol showing the		-	5.0	
Pulsed Diode Forward Current ^a	I _{SM}	integral revers p - n junction		-	-	21	A
Body Diode Voltage	V _{SD}	T _J = 25 °C	$I_{S} = 3.8 \text{ A}, V_{GS} = 0 \text{ V}^{b}$	-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T. =	25 °C, I _F = 3.8 A,	-	650	980	ns
Body Diode Reverse Recovery Charge	Q _{rr}		/dt = 100 A/µs ^b	-	3.8	5.7	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time is negligible (turn	-on is dor	ninated h	ov L _s and	Ln)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

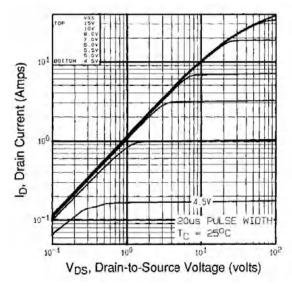


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

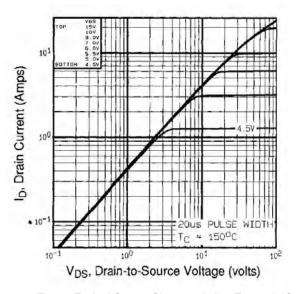


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

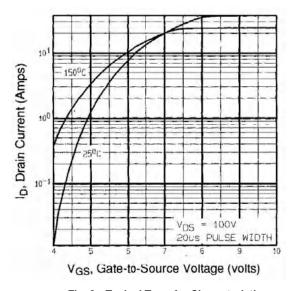


Fig. 3 - Typical Transfer Characteristics

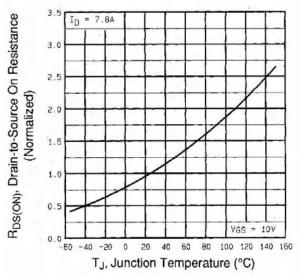


Fig. 4 - Normalized On-Resistance vs. Temperature



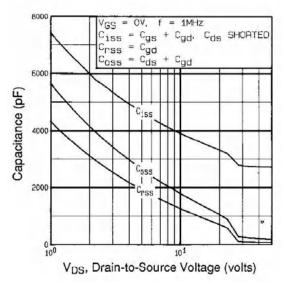


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

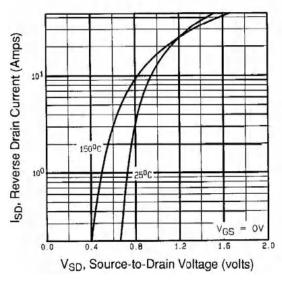


Fig. 7 - Typical Source-Drain Diode Forward Voltage

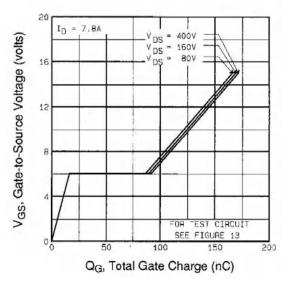


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

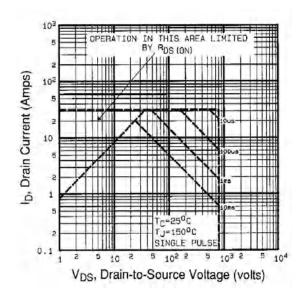


Fig. 8 - Maximum Safe Operating Area



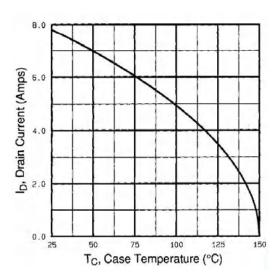


Fig. 9 - Maximum Drain Current vs. Case Temperature

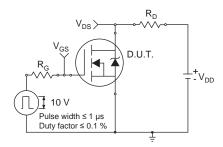


Fig. 10a - Switching Time Test Circuit

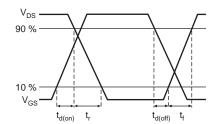


Fig. 10b - Switching Time Waveforms

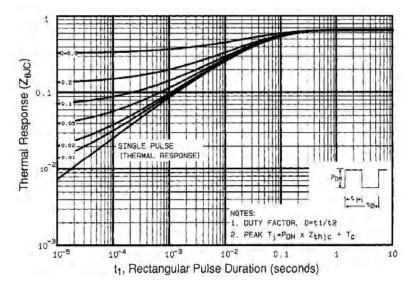


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



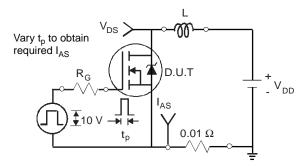


Fig. 12a - Unclamped Inductive Test Circuit

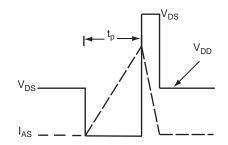


Fig. 12b - Unclamped Inductive Waveforms

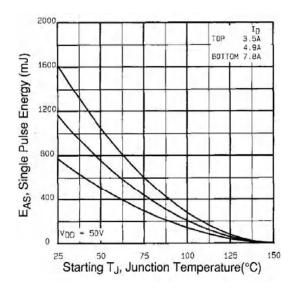


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

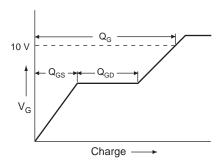


Fig. 13a - Basic Gate Charge Waveform

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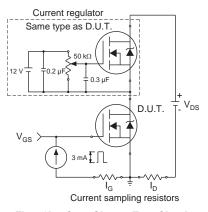
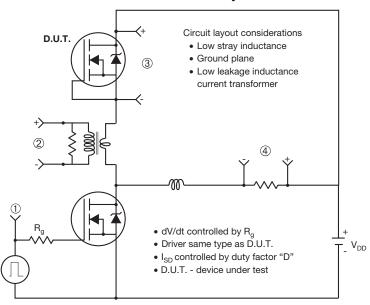


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



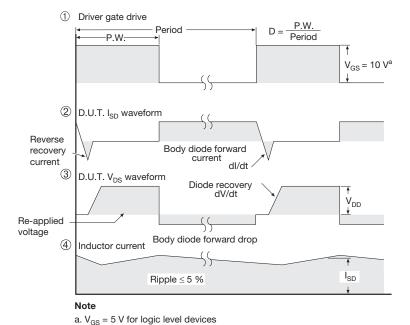
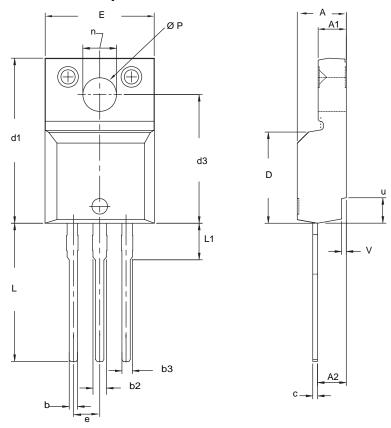


Fig. 14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



	MILLIMETERS		INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.570	4.830	0.180	0.190	
A1	2.570	2.830	0.101	0.111	
A2	2.510	2.850	0.099	0.112	
b	0.622	0.890	0.024	0.035	
b2	1.229	1.400	0.048	0.055	
b3	1.229	1.400	0.048	0.055	
С	0.440	0.629	0.017	0.025	
D	8.650	9.800	0.341	0.386	
d1	15.88	16.120	0.622	0.635	
d3	12.300	12.920	0.484	0.509	
Е	10.360	10.630	0.408	0.419	
е	2.54	2.54 BSC		0.100 BSC	
L	13.200	13.730	0.520	0.541	
L1	3.100	3.500	0.122	0.138	
n	6.050	6.150	0.238	0.242	
ØΡ	3.050	3.450	0.120	0.136	
u	2.400	2.500	0.094	0.098	
V	0.400	0.500	0.016	0.020	

Notes

- To be used only for process drawing.
 These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
 All critical dimensions should C meet C_{pk} > 1.33.
 All dimensions include burrs and plating thickness.
 No chipping or package damage.



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